

Dual N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^a	Q _g (Typ.)		
30	0.0026 at V _{GS} = 10 V	25	26.5 nC		
	0.0032 at V _{GS} = 4.5 V	21	20.5 110		

 D_1 D_1 D_2

 D_2

SO-8

Top View

 S_2

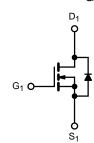
FEATURES

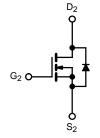
- · Halogen-free
- TrenchFET® Power MOSFET
- 100 % R_g and UIS Tested



APPLICATIONS

- DC/DC Conversion
 - Low-Side Switch
- Notebook PC
- Gaming





N-Channel MOSFET

N-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	30	V	
Gate-Source Voltage		V_{GS}	± 20	v	
	T _C = 25 °C		25		
Continuous Drain Current (T _{.I} = 150 °C)	T _C = 70 °C	I _D	21		
Continuous Brain Gunent (1) = 100 G)	T _A = 25 °C	'D	18.5 ^{b, c}		
	T _A = 70 °C		15.1 ^{b, c}	Α	
Pulsed Drain Current		I _{DM}	70		
Continuous Source-Drain Diode Current	T _C = 25 °C	1-	5.4		
	T _A = 25 °C	'S	2.7 ^{b, c}		
Single Pulse Avalanche Current	I _ 0.1 m∐	I _{AS}	40		
Avalanche Energy L = 0.1 mH		E _{AS}	80	mJ	
	T _C = 25 °C		6.0		
Maximum Power Dissipation	T _C = 70 °C	P _D	3.3	w	
Maximum Fower Dissipation	T _A = 25 °C		3.0 ^{b, c}	VV	
	T _A = 70 °C	1	1.9 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stq}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	33	42	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	16	21	7 0/ **		

Notes:

- a. Based on T_C = 25 °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s
- d. Maximum under Steady State conditions is 85 °C/W.



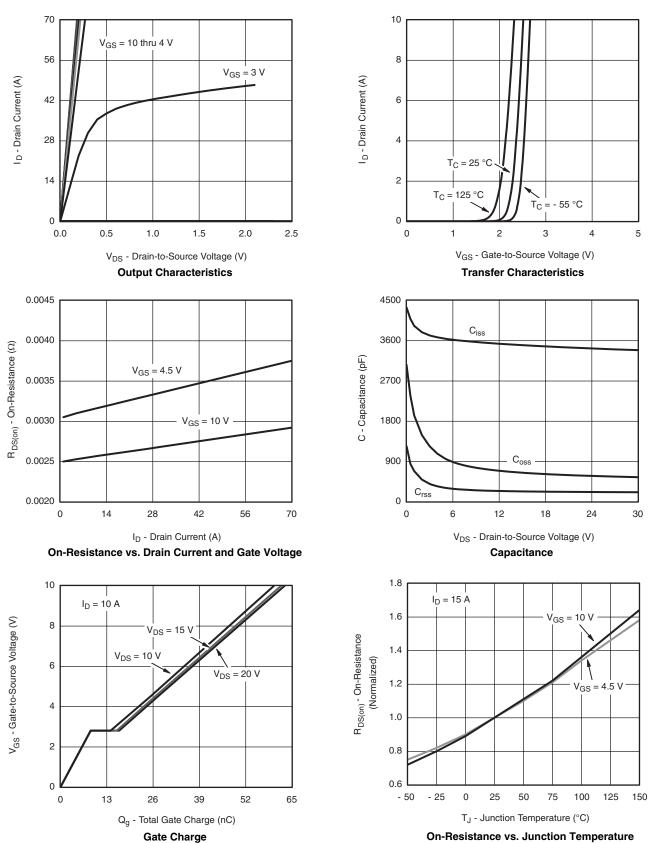
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	30			V
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	J 050 A		27		mV/°0
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	- I _D = 250 μA		- 5.6		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.2		2.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zana Oaka Walkana Busin Oamani	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V			1	
Zero Gate Voltage Drain Current		V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			10	μΑ
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α
		V _{GS} = 10 V, I _D = 15 A	0.0026 0.0032			Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$				
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 15 A		75		S
Dynamic ^b				<u>I</u>		
Input Capacitance	C _{iss}			3545		pF
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		650		
Reverse Transfer Capacitance	C _{rss}			240		
Total Gate Charge		V _{DS} = 15 V, V _{GS} = 10 V, I _D = 10 A		62	95	nC
				26.5	40	
Gate-Source Charge	Q_gs	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$		8.5		
Gate-Drain Charge	Q_{gd}]		7.3		
Gate Resistance	R_g	f = 1 MHz	0.2	1.1	2.2	Ω
Turn-On Delay Time	t _{d(on)}			35	60	
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 1.5 \Omega$		16	30	ns
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		48	85	
Fall Time	t _f			16	30	
Turn-On Delay Time	t _{d(on)}			18	35	
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 1.5 \Omega$		8	16	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		41	75	
Fall Time	t _f			8	18	
Drain-Source Body Diode Characteristi	cs					
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			5.4	
Pulse Diode Forward Current ^a	I _{SM}				70	Α
Body Diode Voltage	V_{SD}	I _S = 3 A		0.72	1.1	V
Body Diode Reverse Recovery Time	t _{rr}			33	65	ns
Body Diode Reverse Recovery Charge	Q _{rr}	L = 10 A dl/dt = 100 A/vo T = 25 °C		27	54	nC
Reverse Recovery Fall Time	t _a	t_a		17		ns
Reverse Recovery Rise Time	t _b			16		

Notes:

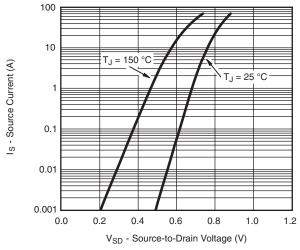
- a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

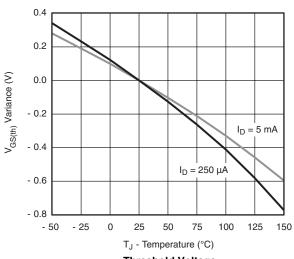


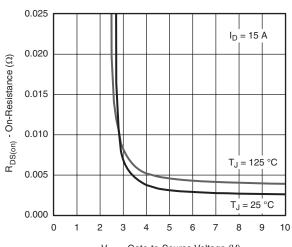






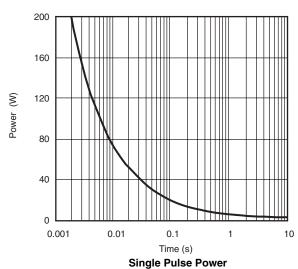
Source-Drain Diode Forward Voltage



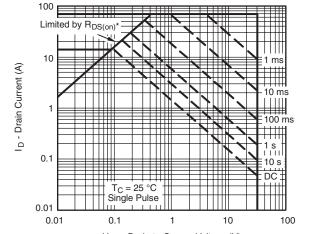


V_{GS} - Gate-to-Source Voltage (V)





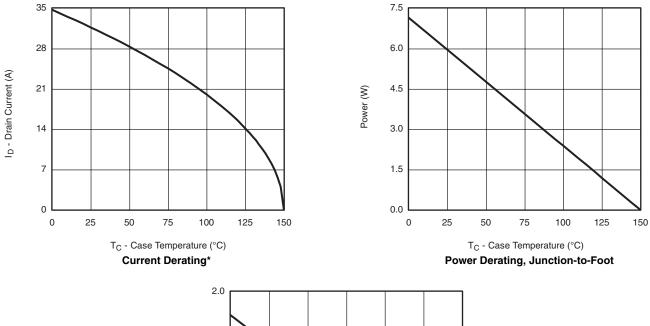
Threshold Voltage

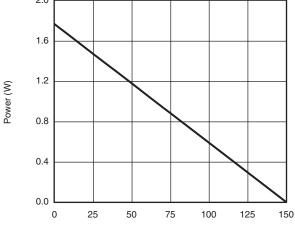


 $V_{DS} \text{ - Drain-to-Source Voltage (V)} \\ ^*V_{GS} > \text{ minimum V}_{GS} \text{ at which R}_{DS(on)} \text{ is specified}$

Safe Operating Area, Junction-to-Ambient





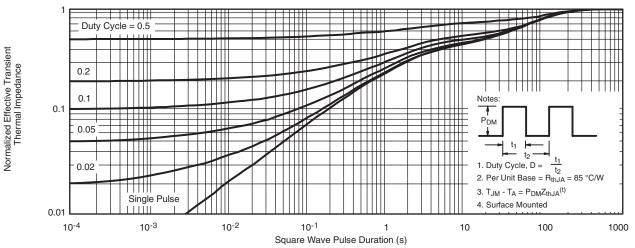


T_A - Ambient Temperature (°C)

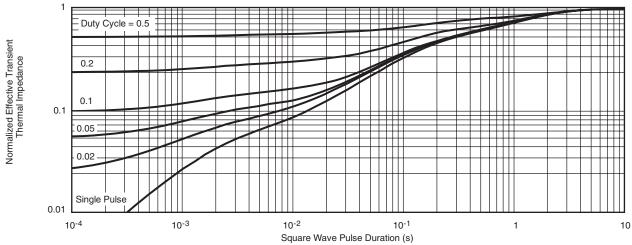
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





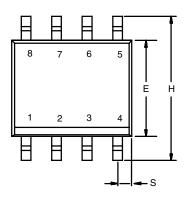
Normalized Thermal Transient Impedance, Junction-to-Ambient

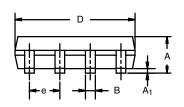


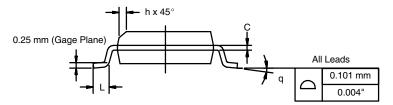
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







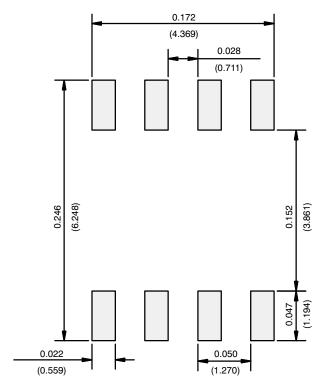
	MILLIM	IETERS	INC	INCHES		
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
Е	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050 BSC			
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Rev. I, 11-Sep-06						

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DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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